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ORIGINAL

Application/Control No.

10692660

Examiner ZHENG WEI 2192

Applicant(s)/Patent Under Reexamination MCCOLLUM ET AL. Art Unit

INTERNATIONAL CLASSIFICATION

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/ZHENG WEI/ Examiner.Art Unit 2192	11/08/2008	Total Claims Allowed: 27			
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/TUAN Q DAM/ Supervisory Patent Examiner.Art Unit 2192	11/10/2008	O.G. Print Claim(s)	O.G. Print Figure		
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